Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/523,992	JEONG, CHANG LOG
Examiner	Art Unit
David E. Bochna	3679

SEARCHED

Class	Subclass	Date	Examiner
285	319	8/25/2006	DB
	307		
	317		
	321		
	340		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner